

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/647,742	DAVIDSON, MARK P.	
Examiner		Art Unit		Page 1 of 1
Samuel A. Turner		2877		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	See et al , Scanning optical microellipsometer for pure surface profiling, Applied Optics, 12-1996, pp 6663-6668.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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